

Spring-loaded test probe

GKS-001 303 150 A 0600

Item GKS-001-0020



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Partner for Future Technology

- Robust, compact design for harsh ICT/FCT applications with limited space
- For optimum contact at the test points (e.g. pads, vias, and pins), various tip styles in different diameters and finishes, as well as various spring forces are available.

INGUN SELECTION

General data

| | |
|--------------------------------|---|
| Product group | ICT / FCT (in-circuit test and function test) |
| Sub-product group | Short/robust GKS |
| Series | GKS-001 |
| Grid | 1.91 mm [75 mil] |
| Contacting from | Pin, Post |
| Magnetic | Yes |
| Installation type | Plug-in |
| Quick-exchange system | Yes |
| Adjustable installation height | No |
| Non-rotating | No |
| Compatible receptacle(s) | KS-001 |
| Min. temperature | - 40 °C [- 104 °F] |
| Max. temperature | + 80 °C [+ 176 °F] |
| RoHS-compliant | Yes |

Electrical data

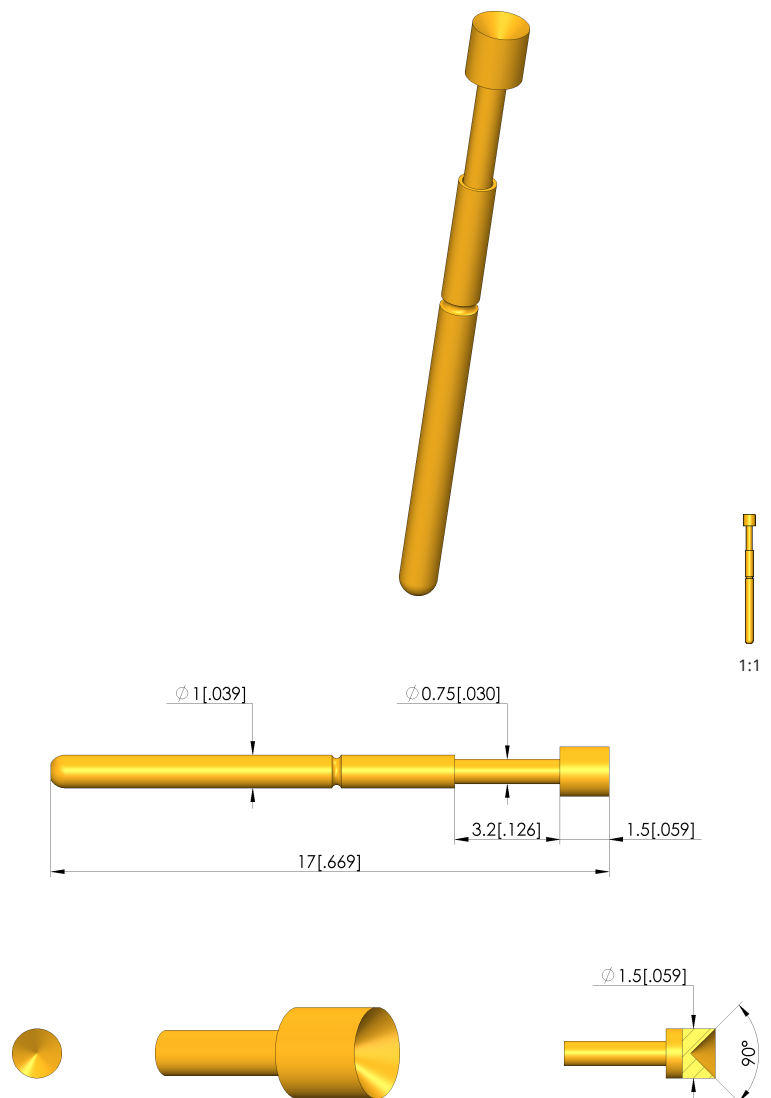
| | |
|---------------------------------------|----------|
| Current load capacity / rated current | 3 A |
| Typical resistance (Ri) | <20 mOhm |

Mechanical data

| | |
|--------------------------------|-------------------|
| Total length | 17 mm [.669 in] |
| Barrel diameter | 1 mm [.039 in] |
| Maximum stroke | 3 mm [.118 in] |
| Spring pre-load | 0.23 N [.827 ozf] |
| Collar height | 00 |
| Spring force at working stroke | 0.6 N [2.15 ozf] |
| Recommended working stroke | 2.4 mm [.094 in] |

Tip style data

| | |
|--------------------|------------------|
| Tip style | 03 inverse cone |
| Tip diameter | 1.5 mm [.059 in] |
| Tip style surface | A gold |
| Tip style material | 3 CuBe |



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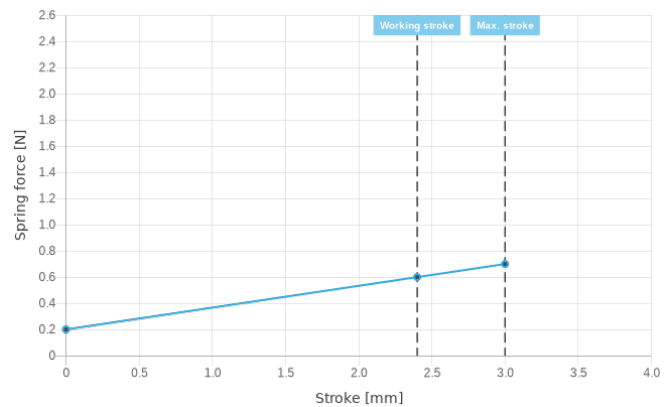
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INGUN Prüfmittelbau GmbH

Max-Stromeyer-Straße 162
78467, Constance, Germany
Phone +49 7531 8105-0
Customer hotline +49 7531 8105-888
Fax +49 7531 8105-65
info@ingun.com



Prices and delivery times on request.
Technical changes reserved. 12/22 EN

Weitere Informationen zum Thema
ICT/FCT Test probes

